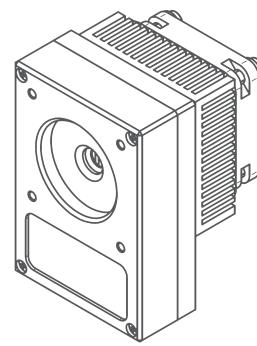


UHSM-I-10.6

Ultra-high-speed IR detection module based on HgCdTe TE cooled optically immersed photovoltaic detector



FEATURES

- Spectral range: 3.0 to 12.0 μm
- Frequency bandwidth: 300 Hz to 900 MHz (typ.)
- High performance and reliability
- DC monitor
- Single power supply
- Integrated TEC controller and fan
- M4 mounting hole
- Compatible with optical accessories
- Quantity discounted price
- Fast delivery
- No minimum order quantity required

APPLICATIONS

- Dual-comb spectroscopy
- Heterodyne detection
- Characterization of pulsed laser sources
- LIDARs
- Object scanners
- Time-resolved fluorescence spectroscopy systems
- Free-space optical communication
- Telemetry

INCLUDED ACCESSORIES

- 2 pcs of SMA-BNC cable
- 1 pc of AC adaptor

DEDICATED ACCESSORIES

- OTA optical threaded adapter (p. 155)
- DRB-2 base mounting system (p. 152)

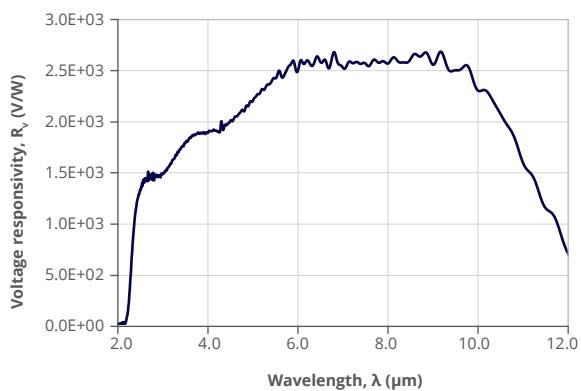
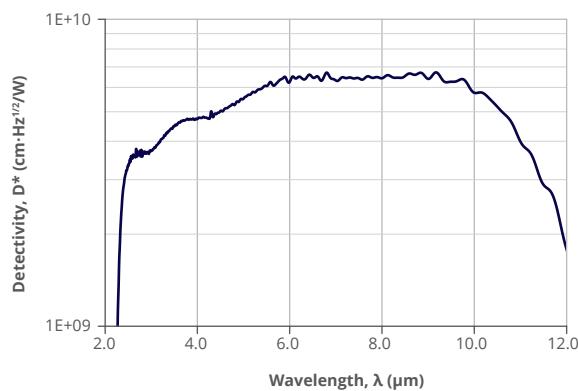
DETECTION MODULE CONFIGURATION

| Detection module symbol | UHSM-I-10.6 |
|--------------------------|--|
| Detector type | photovoltaic |
| Active element material | epitaxial HgCdTe heterostructure |
| Optical area, A_o | 1 mm \times 1 mm |
| Immersion | hyperhemisphere |
| Cooling | 4TE |
| Acceptance angle, Φ | ~36 deg. |
| Window | wZnSeAR (3 deg. wedged zinc selenide, anti-reflection coating) |
| Preamplifier type | transimpedance |
| Signal output socket | SMA |
| DC monitor output socket | SMA |
| Power supply socket | DC 2.1/5.5 |

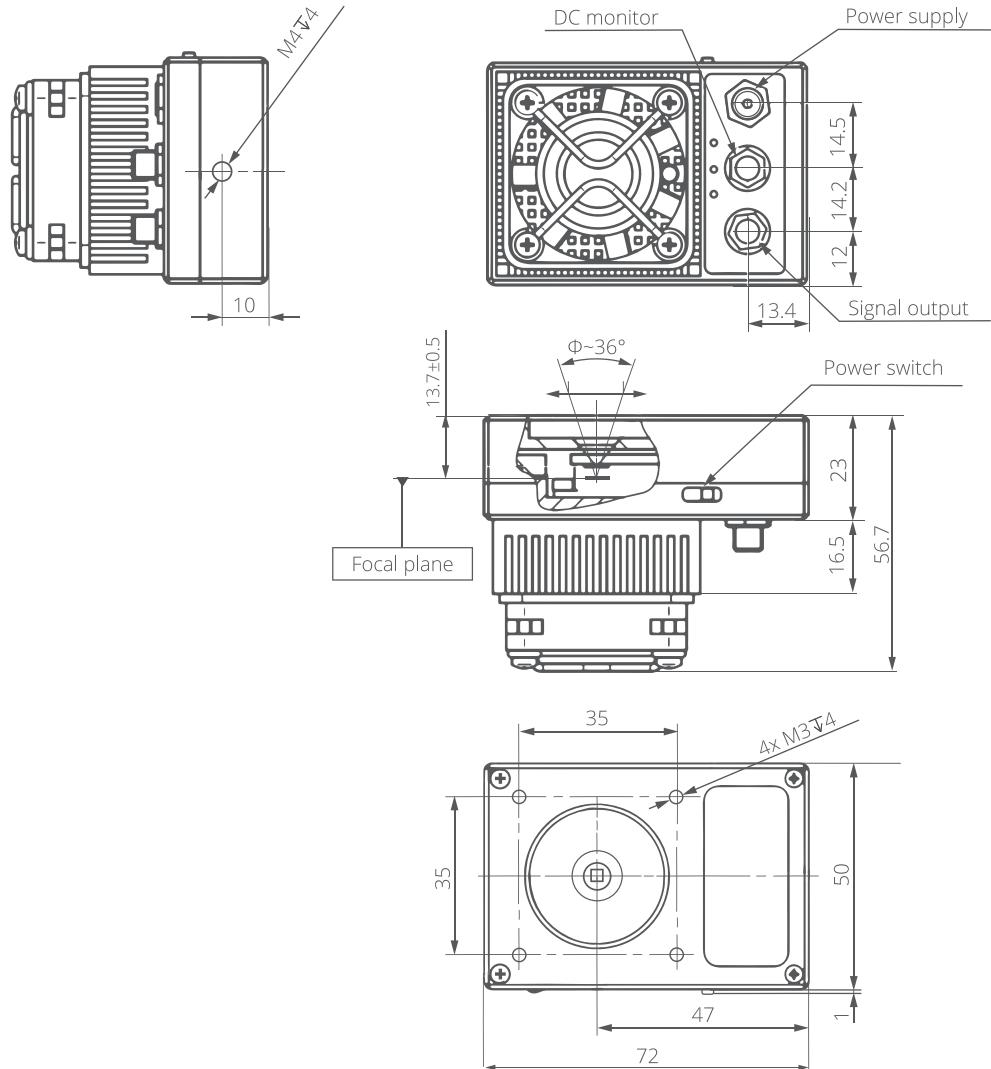
SPECIFICATION ($T_{\text{amb}} = 293 \text{ K}$, $R_{\text{load}} = 50 \Omega$, unless otherwise noted)

| Parameter | Test conditions/remarks | Value | | | Unit |
|---|--|-------------------|-------------------|------|--|
| | | Min. | Typ. | Max. | |
| Active element temperature, T_{chip} | | - | 215 | - | K |
| Cut-on wavelength, $\lambda_{\text{cut-on}} (10\%)$ | At 10% of peak responsivity | - | 3.0 | - | μm |
| Peak wavelength, λ_{peak} | | 7.0 | 8.0 | 9.0 | μm |
| Specific wavelength, λ_{spec} | | - | 10.6 | - | μm |
| Cut-off wavelength, $\lambda_{\text{cut-off}} (10\%)$ | At 10% of peak responsivity | - | 12.0 | - | μm |
| Detectivity, D^* | At $\lambda = \lambda_{\text{peak}}$, $f = 100 \text{ MHz}$ | - | 6.7×10^9 | - | $\text{cm} \cdot \text{Hz}^{1/2}/\text{W}$ |
| | At $\lambda = \lambda_{\text{spec}}$, $f = 100 \text{ MHz}$ | 2.0×10^9 | 5.0×10^9 | - | $\text{cm} \cdot \text{Hz}^{1/2}/\text{W}$ |
| Output noise voltage density, v_n | At $f = 100 \text{ MHz}$ | - | - | 70 | $\text{nV}/\text{Hz}^{1/2}$ |
| Voltage responsivity, R_v | At $\lambda = \lambda_{\text{peak}}$ | - | 2.7×10^3 | - | V/W |
| | At $\lambda = \lambda_{\text{spec}}$ | 7.0×10^2 | 2.0×10^3 | - | V/W |
| Low cut-off frequency, f_{lo} | | - | 300 | - | Hz |
| High cut-off frequency, f_{hi} | | 0.7 | 0.9 | - | GHz |
| Output impedance, R_{out} | | - | 50 | - | Ω |
| Output voltage swing, V_{out} | | - | - | ±1 | V |
| 1/f corner frequency, f_c | | - | - | 10 | MHz |
| Voltage responsivity, R_v | At $\lambda = \lambda_{\text{peak}}$, DC monitor | 3.8×10^3 | - | - | V/W |
| | At $\lambda = \lambda_{\text{spec}}$, DC monitor | 2.7×10^2 | - | - | V/W |
| Low cut-off frequency, f_{lo} | DC monitor | - | 0 | - | Hz |
| High cut-off frequency, f_{hi} | DC monitor | - | 260 | - | Hz |
| Output voltage offset, V_{off} | | - | - | ±20 | mV |
| Power supply voltage, V_{sup} | | - | 9 | - | V |
| Power supply current consumption, I_{sup} | | - | - | 1.2 | A |
| Weight Value | | - | 235 | - | g |

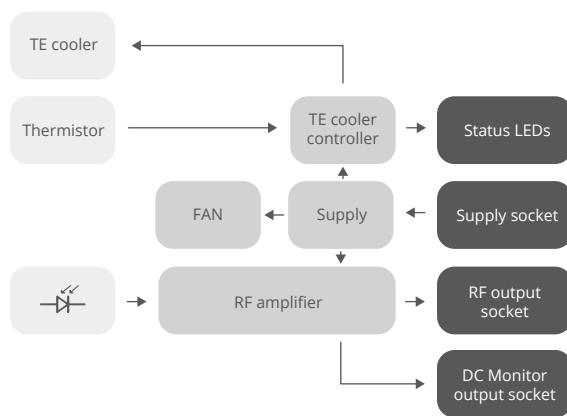
SPECTRAL RESPONSE (Typ., $T_{\text{amb}} = 293 \text{ K}$, $T_{\text{chip}} = 215 \text{ K}$)



MECHANICAL LAYOUT (Unit: mm)



SCHEMATIC DIAGRAM



ABSOLUTE MAXIMUM RATINGS

| Parameter | Test conditions/ remarks | Value | Unit |
|--|---|-----------|--------------------|
| Ambient operating temperature, T_{amb} | | 10 to 30 | °C |
| Storage temperature, T_{stg} | | -20 to 50 | °C |
| Humidity | No dew condensation | 10 to 90 | % |
| Maximum incident optical power density | Continuous wave (CW) or single pulses >1 μ s duration | 2.5 | W/cm ² |
| | Single pulses <1 μ s duration | 10 | kW/cm ² |

Stresses beyond those listed under absolute maximum ratings may cause permanent damage to the device. Constant or repeated exposure to absolute maximum rating conditions may affect the quality and reliability of the device.